

<b>Notice of References Cited</b>	Application/Control No. 10/534,274	Applicant(s)/Patent Under Reexamination HIRANO ET AL.	
	Examiner Pablo N. Tran	Art Unit 2618	Page 1 of 1

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*	B	US-7,020,445	03-2006	Miya, Kazuyuki	455/101
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